Artificial Intelligence Assisted Diagnosis Techniques in Smart Manufacturing

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Message from the Guest Editors

Dear Colleagues,

Nowadays, with the rapid advancement of artificial intelligence (AI), various AI techniques have been applied to ensure equipment and production reliability, safety, and quality, and to prevent unexpected failures in the smart manufacturing. The boosting of the applications of AI techniques brings new opportunities in the smart manufacturing, including intelligent fault diagnosis, prognosis, and surface defect detection. These AI-assisted techniques can usually handle various industrial signals or images to monitor the health of the machines or the products, which have shown a great potential to improve the safety and efficiency of the smart manufacturing. The proposed Special Issue on Artificial Intelligence-Assisted Diagnosis Techniques in Smart Manufacturing focus on the theories, the methodologies, as well as the applications of AI techniques in smart manufacturing. Researchers can use various industrial data (such as signals, images, or videos) to diagnose and predict the state of the machines or the products.

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Special Issue

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Message from the Editor-in-Chief

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